Supplementary Information

Texture design of electrode for efficiency enhancement of organic solar cells

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Table S1. Summary of the photovoltaic performance of ITO/MoO₃/P3HT:PCBM/A1 devices with the ITO anodes eroded for different times by using PS nanospheres as etching mask. The parameters were averaged with 8 cells for each type of the devices.

ITO eroding time (min)	$J_{\rm sc}({\rm mA/cm}^2)$	$V_{oc}(V)$	FF (%)	PCE (%)
0	8.12±0.14	0.62 ± 0.02	0.55 ± 0.02	2.75 ± 0.04
2.0	8.07±0.17	0.64 ± 0.02	0.57 ± 0.04	2.95 ± 0.03
2.5	8.37±0.12	0.65 ± 0.02	0.59 ± 0.02	3.19±0.02
3.0	8.15±0.15	0.65 ± 0.02	0.57 ± 0.03	3.03 ± 0.03
3.5	7.84 ± 0.23	0.64 ± 0.02	0.52 ± 0.02	2.60 ± 0.01



Figure S1. Typical SEM images of ITO anodes eroded for different times. (a) Assembled PS nanospheres on ITO; (b) Eroded for 2.0 min; (c) and (d) Eroded for 2.5 min; (e) Eroded for 3.0 min; (f) Eroded for 3.5 min.



Figure S2. Erosion temperature effect on ITO surface with fixed eroding time of 2.5 min. (a) Eroding temperature of 10 °C, RMS roughness of 2.10 nm; (b) Eroding temperature of 20 °C, RMS roughness of 4.89 nm; (c) Eroding temperature of 35 °C, RMS roughness of 0.47 nm; and (d) Eroding temperature of 50 °C, RMS roughness of 0.17 nm. Left panel is AFM image and right panel is corresponding SEM image. In the case of eroding at 50 °C, the ITO layer on the glass is completely etched away.



Figure S3. Schematic diagram of fabricated P3HT:PCBM bulk heterojunction solar cells with textured ITO anode and PEDOT:PSS as anode buffer layer.

Table S2.Summary of the photovoltaic performance ofITO/PEDOT:PSS/P3HT:PCBM/Al devices with the ITO anode eroded with HCl fordifferent timed by using PS nanospheres as etching mask.

ITO eroding time (min)	$Jsc(mA/cm^2)$	Voc(V)	FF(%)	η(%)
0	8.03	0.64	0.55	2.85
2.0	8.02	0.64	0.53	2.73
2.5	8.28	0.64	0.55	2.89
3.0	8.11	0.64	0.53	2.76
3.5	7.93	0.62	0.55	2.70



Figure S4. The *J*-V curves of the ITO/PEDOT:PSS/P3HT:PCBM/Al solar cells with the ITO anodes eroded for different times. The *J*-V curves were measured under 100 mW/cm² AM 1.5G solar illumination.



Figure S5. Typical AFM images of the P3HT:PCBM active layer on ITO/PEDOT:PSS with the ITO eroded for (a) 0 min (RMS roughness of 0.82 nm); (b) 2.0 min (RMS roughness of 0.87 nm); (c) 2.5 min (RMS roughness of 0.90 nm); (d) 3.0 min (RMS roughness of 0.88 nm); (e) 3.5 min (RMS roughness of 0.84 nm). The scanning size of the images is 5 μ m × 5 μ m.



Figure S6. Optical properties of solar cells built on ITO anodes eroded for different times with PEDOT:PSS as anode buffer layer. (a) Absorption spectra of P3HT:PCBM on ITO/PEDOT:PSS with patterned or planar ITO anodes; (b) The full reflectance spectra of ITO/PEDOT:PSS/P3HT:PCBM with patterned or planar ITO anodes.